



Date Created: 2/9/2004  
Date Issued: 4/9/2004  
PCN # 20040607

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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REL Engineer

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PCN Type: Alternate Fab Location

Effectivity

Expected 1st Device Shipment Date: 7/9/2004  
Earliest Year/Work Week of Changed Product: 0428  
(Note: Package marking may differ from this format)

Product ID (Description):

The product affected by this change is listed below in the "Affected FSIDs" section.

Description of Change:

As part of Fairchild Semiconductor's effort to provide value added products in the SuperSOT-6 package and continue to improve customer service, we are planning to transfer the wafer fabrication manufacturing site from our foundry Fabtech to Fairchild Semiconductor fabrication site located in West Jordan, UT. This fabrication site has been our premier fabrication for more than the past 5 years and is a QS-9000 and ISO-9000 certified facility.

Effect of Change:

This change will have no adverse impact on any of the electrical parameters for the product involved. The product test conditions, test limits and performance will remain unchanged. Product will be built with the same level of quality and reliability as our current products.

Qualification:

See qualification results are listed below.

Qual/REL Plan Numbers

Additional Qualification Data

**RELIABILITY TEST RESULT SUMMARY**

TEST	CONDITION	REL #	220452	220453	220454
		DEVICE	FDP794P	FDP794P	FDP794P
		CHIP	TTBFA37	TTBFA37	TTBFA37
		PKG	TO-220	TO-220	TO-220
		DURATION	# OF FAILURES	# OF FAILURES	# OF FAILURES
Op Life	25°C	1000 hrs	<b>0/77</b>	<b>0/77</b>	<b>0/77</b>
HTRB	150°C, Vr=80% Bvdss	1000 hrs	<b>0/77</b>	<b>0/77</b>	<b>0/77</b>
Autoclave	12l C, 15 psi	96 hrs	<b>0/77</b>	<b>0/77</b>	<b>0/77</b>
Temp Cycle	-65°C TO 150°C, 15MIN DWELL	500 cyc	<b>0/77</b>	<b>0/77</b>	<b>0/77</b>
Hast	130°C/85%RH Vr=80% Bvdss	96hrs	<b>0/77</b>	<b>0/77</b>	<b>0/77</b>

Affected FSIDs

FDC6392S